Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/798,378	ANACLERIO ET AL.	
Examiner	Art Unit	
Tan V. Mai	2193	

SEARCHED					
Class	Subclass	Date	Examiner		
708	819	6/1/2007	MAI		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
·	DATE	EXMR	
Inventor(s) search Double Patent Check Data Bases Search (see search history printout(s))	6/1/2007	MAI	
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